Notice of References Cited

Application/Control No.	Applicant(s)/Pater Reexamination	nt Under
10/062,193	TEIG ET AL.	
Examiner	Art Unit	
Phallaka Kik	2825	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,839,823	06-1989	Matsumoto, Yoshihiro	706/52
v; ·	В	US-6,446,027	09-2002	O'Keeffe et al.	702/183
	С	US-6,304,836	10-2001	Krivokapic et al.	703/14
	D	US-5,642,296	06-1997	Saxena, Sharad	702/84
	E	US-5,822,218	10-1998	Moosa et al.	716/4
	F	US-5,276,632	01-1994	Corwin et al.	703/2
	G	US-2002/0075383	06-2002	Trobaugh et al.	348/42
	Н	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ö					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Brandt et al., "Circuit multi-fault diagnosis and prediction error estimation using a committee of Bayesian neural networks", IEE Colloquium on Testing Mixed Signal Circuits and Systems, 23 October 1997, pp. 7/1-7/7.
	٧	Niu et al., "A Bayesian approach to variable screening for modeling the IC fabrication process", 1995 IEEE International Symposium on Circuits and Systems, Vol. 2, 30 April 1995, pp. 1227-1230.
	w	Ida et al., "Bayesian analysis in manufacturing instrumentation for test and evulation", IEEE Conference Record of 1993 Fourth Fifth Annual Conference of Electrical Engineering Problems in the Rubber and Plastics Industries, 27 April 1993, pp. 4-13.
	x	Kolehmainen et al., "A Bayesian approach and total variation priors in 3D electrical impedance tomography", Proceedings of th 20th Annual International Conference of the IEEE Engineering in Medicine and Biology Society, Vol. 2, 29 October 1998, pp. 1028-1

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

	_		
Application/Control No.	•	Applicant(s)/Pater	nt Under
10/062,193		Reexamination TEIG ET AL.	_
Examiner		Art Unit	
Phallaka Kik		2825	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-			
	В	US-			
	С	US-			
	۵	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	Zhang et al., "Confidence regions for cascaded neural network prediction in power markets", 2001 Power Engineering Society Winter Meeting, Vol. 2, 28 January 2001, pp. 533-538.					
	٧	Vehtari et al., "Bayesian neural networks for industrial applications", Proceedings of the 1999 IEEE Midnight-Sun Workshop on Soft Computing Methods in Industrial Applications, 16 June 1999, pp. 63-68.					
	w	NN9107436, "Maximum Likelihood Training of Probabilistic Linear Functions (Probabilistic Perceptrons)", IBM Technical Disclosure Bulletin, Vol. 34, No. 2, July 1991, pp. 436-442 (8 pages).					
	х						

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.